

# Advanced Test Equipment Rentals - www.atecorp.com 800-404-ATEC (2832)

# Specifications



#### **UCS 200M**

Ultra-Compact Simulator for Automotive Transients

Designed to meet the many test needs of today and the rigours of converging world standards, the EM Test UCS 200M generator offer a full range of conducted immunity transient tests to ISO, JASO, SAE and manufacturer standards.

The distinct operation features, convenient DUT connection facilities, a clearly arranged menu structure and display philosophy as well as the preprogrammed standard test routines make testing easy, reliable and safe. Extendable by a large variety of test accessories the UCS 200M is the universal equipment for a wide range of recommendations even for high power battery supply application up to 200A.

- ISO 7637-2-2004
- SAE J1113 parts 11, 12
- SAE J1455
- JASO D001
- GM 3097
- Ford ES-XW7T
- Chrysler PF9326
- DC 10614
- BMW
- VW
- PSA
- Renault
- FiatNissan
- Honda





### Burst module, Pulse 3a/3b Electrical Fast Transient Simulator based on ISO 7637-2:2004

### Coupling Matrix type CNA

Test Level Output	
acc. to ISO 7637-2:2004	
Test voltage	25V - 1'000V ± 10%
Rise time tr	5ns ± 1.5ns
Pulse duration td	100ns (+100/-0)ns
Verification	As per Annex D of ISO 7637-2:2004 into a
	$50\Omega$ and a 1,000 $\Omega$ load
Source impedance	$Zq = 50\Omega$
Polarity	Pulse 3b positive and pulse 3a negative
	! !
Trigger Circuit	
Trigger of bursts	Automatic, manual, external
Burst duration	T4 = 0.1ms - 999.9ms
Burst repetition rate	T5 = 10ms - 9,999ms
Spike frequency	f = 0.1kHz - 200kHz
Test duration	T = 0:01min - 999:59min or endless
Outputs	
Direct	Via 50Ω-coaxial connector
Coupling mode	To the + battery line
CRO trigger	5V trigger signal for oscilloscope
Test Routines	
Quick Start	On-line adjustable parameters, easy to use
Standard Test Routines	acc. to ISO 7637-2:2004, level 1 - 4
	<u> </u>
User Test Routines	User Test Routines
	Random burst release
	Change voltage after T by ∆T
	Change frequency after T by ∆f
CRO trigger	5V trigger signal for oscilloscope

Technical data for sta	ndard CNA 50
DUT supply voltage	Max. 60V
DUT supply current	50 A
Inrush current capability	100A for 500ms
Dimension UCS & CN	19" / 3HU
Dimension 666 & 614	
Technical data for opt	ional CNA 100
DUT supply voltage	Max. 60V
DUT supply current	100 A
Inrush current capability	150A for 500ms
Dimension UCS & CN	19" / 6HU
Technical data for opt	
DUT supply voltage	Max. 60V
DUT supply current	150 A
Inrush current capability	150 A
Dimension UCS & CN	19" / 9HU
Technical data for opt	
DUT supply voltage	Max. 60V
DUT supply current	200 A
Inrush current capability	200 A
Dimension UCS & CN	19" / 9HU
Input	
DUT supply +/-	Simulator type VDS 200B & PFS 200B
Pulse 5, 7	Standard for one type LD 200x
Output	
+/- DUT supply	Central DUT output
Coaxial output port	To connect the capacitive coupling clamp as per ISO 7637 part 3
Interface	
CN interface	To control the internal CN by external pulse generators such as LD 200B

Options	
ACC	Capacitive coupling clamp acc. to ISO 7637 part 3
KW50	100:1 divider, $50\Omega$
KW1000	400:1 divider, 1000 $\Omega$
CA EFT kit	EFT/Burst verification kit
A6dB	6dB attenuator, $50\Omega$
ITP	Immunity test probes (electrical field generation)
ITP/H	Immunity test probes (magnetic field generation

Option	
CNA Ext	Extention to connect 3 additional generators



## Micropulse module, Pulse 1, 2 based on ISO 7637-2:2004

Test Level Output	
Open circuit voltage	$U = 20V - 600V \pm 10\%$ ( Peak voltage
- CC - 1	and polarity acc. to the selected standard)
Repetition rate	0.2s - 99.0s
100 D. L 4 (40) ()	!
ISO Pulse 1 (12V)	
Rise time tr (10 - 90%)	1µs + 0% // - 50%
Pulse duration td (10 - 10%)	2ms ± 10%
Internal resistor	$10\Omega \pm 10\%$
ISO Pulse 1 (24V)	
Rise time tr (10 - 90%)	3µs + 0% // - 50%
Pulse duration td (10 - 10%)	$1\text{ms}\pm10\%$
Internal resistor	$50\Omega \pm 10\%$
ISO Pulse 2 (12V/24V)	
Rise time tr (10 - 90%)	1µs + 0% // - 50%
Pulse duration td (10 - 10%)	50μs ± 10%
Internal resistor	$2\Omega \pm 10\%$
	1
As per ISO 7637-2 the f	ollowing standards can be covered
SAE J1113	GM 3097
BMW	VW
Chrysler PF 9326	PSA
DC10614	Renault
FIAT	Mitsubishi
Ford ES-XW7T	Honda
1 614 26 77771	i
Option Pulse Progran	aming Mode
Rise time	
Pulse duration	1μs to 10μs with steps of 1μs
	50μs to 10,000us
Internal resitor	$2\Omega$ -100Ω in steps of 5Ω, 200, 400 & 450Ω
Trigger	
Automatic	Automatic release of the pulses
Manual	Manual release of a single pulse
External	External release of a single pulse
Battery supply switch	Selectable Off time, to = 0 – 10,000ms
Output	
+/- output	Central DUT output
Coupling	To the battery +line
Decoupling	Via diode and battery supply switch
	1
Test Routines	
Quick Start	Immediate start; easy to use and fast
User Test Routines	Custom made test routines
	2. Change voltage after n pulses by ΔV
Pulse selctor	i
Service	Service, setup, self test
Interface	
Serial interface	RS 232, baud rate 1200 - 19200
Parallel interface	IEEE 488, address 1 - 30
CN interface	To control the internal CN and battery
OI VIII II	, is some or the internal of and battery
	switch

## Micropulse module, Pulses based on Jaso and Nissan

JASO D 001	
Pulse A2 as per JASO D 001	
Test voltage	+110V
Capacitor	C = 4.7µF
Pulse duration at $\tau$	$\tau(36,8\%)$ = 2.5 $\mu$ s $\pm$ 30%
R1	$0.6\Omega \pm 10\%$
R2	$0.4\Omega\pm10\%$
Polarity	Positive
Pulse B2 as per JASO D	001
Test voltage	-260V
Capacitor	C = 33µF
Pulse duration at $\tau$	$\tau$ (36,8%) = 2.0ms $\pm$ 20%
R1	$60\Omega \pm 10\%$
R2	$80\Omega \pm 10\%$
Polarity	Negative
Pulse D2 as per JASO D 001	
Test voltage	+170V
Capacitor	C = 2.2µF
Pulse duration at $\tau$	$\tau$ (36,8%) = 2.5 $\mu$ s $\pm$ 30%
R1	$1.2\Omega \pm 10\%$
R2	$0.9\Omega\pm10\%$
Polarity	Positive

Niccon NDC	
Nissan NDS	
Pulse B2 as per Nissan	
Open circuit voltage	- 300V ± 10%
Capacitor	C = 33µF
R1	$100\Omega \pm 10\%$
R2	$75\Omega\pm10\%$
Polarity	Negative
Pulse C8 as per Nissar	
Open circuit voltage	$\pm 300 \text{V} \pm 10\%$
Capacitor	C = 1µF
R1	$500\Omega\pm10\%$
R2	$450\Omega\pm10\%$
Polarity	Positive and negative
	1
Pulse C50 as per Nissa	an
Open circuit voltage	±300V ± 10%
Capacitor	C = 33µF
R1	$30\Omega\pm10\%$
R2	$200\Omega \pm 10\%$
Polarity	Positive and negative
•	
Pulse C300 as per Niss	san
Open circuit voltage	- 300V ± 10%
Capacitor	C = 33µF
R1	$100\Omega \pm 10\%$
R2	$75\Omega \pm 10\%$
Polarity	Negative



#### Micropulse module,

Pulses based on SAE J1455

SAE J1455	
Mutual Pulse as per SAE J1455	
1µs +20%	
$15\mu s \pm 20\%$	
$50\Omega \pm 10\%$	
Inductive Pulse as per SAE J 1455	
$1\mu s\pm 20\%$	
$1,000 \mu s \pm 20\%$	
$20\Omega \pm 10\%$	

Options	
Options	
CA ISO	Micropulse/Load Dump pulse verification kit

### General data

General data	
Dimensions, weight	
For models 50A	19" / 3HU, approx. 20kg
For models 100A	19" / 6HU, approx. 30kg
For models 150A and 200A	19" / 9HU, approx. 35kg
Supply voltage	115/230V +10/-15%
Fuses	2 x T 2AT (230V) or 2 x T 4AT (115V)

Options	
	For system integration; includes GPIB bus, pulse bus, ground reference plane, security switch and power contact.
ISMISO	Software to control the test, including standard library, test report facility and data conversion generator.



**Sophisticated Housing for Sophisticated Instruments** 





UCS 200M 200A model

The best place to put your generators is in the SmartRack. A wired, "intelligent" rack, the SmartRack not only holds, but also interconnects and controls equipment. Slide your generators into the SmartRack and you can run entire test routines from your PC with no plugging or unplugging, no stops or starts.

Select from a comprehensive directory of the most recent preprogrammed international and manufacturer standards – including custom pulse waveforms – and the SmartRack does the rest. You can modify test parameters and even create your own tests.

Just how easy is testing with the SmartRack? Consider this:

- The Device Under Test (DUT) voltage has one easy connection at the UCS 200M coupling unit
- No need to keep plugging and unplugging DUTs
- The test rack has a ground reference plane that matches with the test table specified in ISO 7637-2:2004
- ISM ISO (SmartRack) software controls the entire test process. It generates test reports as well
- Tests can be initiated from front panels as well as from a PC

Technical data subject to change without notice.

